



**CY54/74FCT540T
CY54/74FCT541T**

Function Table FCT540T^[1]

Inputs			Output
\bar{OE}_A	\bar{OE}_B	D	
L	L	L	H
L	L	H	L
H	H	X	Z

Maximum Ratings^[2, 3]

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature -65°C to $+150^{\circ}\text{C}$

Ambient Temperature with

Power Applied -65°C to $+135^{\circ}\text{C}$

Supply Voltage to Ground Potential -0.5V to $+7.0\text{V}$

DC Input Voltage -0.5V to $+7.0\text{V}$

DC Output Voltage -0.5V to $+7.0\text{V}$

DC Output Current (Maximum Sink Current/Pin) 120 mA

Power Dissipation 0.5W

Function Table FCT541T^[4]

Inputs			Output
\bar{OE}_A	\bar{OE}_B	D	
L	L	L	L
L	L	H	H
H	H	X	Z

Static Discharge Voltage $>200\text{V}$
(per MIL-STD-883, Method 3015)

Operating Range

Range	Range	Ambient Temperature	V_{CC}
Commercial	CT, DT	0°C to $+70^{\circ}\text{C}$	$5\text{V} \pm 5\%$
Commercial	T, AT	-40°C to $+85^{\circ}\text{C}$	$5\text{V} \pm 5\%$
Military ^[4]	All	-55°C to $+125^{\circ}\text{C}$	$5\text{V} \pm 10\%$

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	Min.	Typ. ^[5]	Max.	Unit
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$, $I_{OH} = -32\text{ mA}$	2.0			V
		$V_{CC} = \text{Min.}$, $I_{OH} = -15\text{ mA}$	2.4	3.3		V
		$V_{CC} = \text{Min.}$, $I_{OH} = -12\text{ mA}$	2.4	3.3		V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$, $I_{OL} = 64\text{ mA}$		0.3	0.55	V
		$V_{CC} = \text{Min.}$, $I_{OL} = 48\text{ mA}$		0.3	0.55	V
V_{IH}	Input HIGH Voltage		2.0			V
V_{IL}	Input LOW Voltage				0.8	V
V_{II}	Hysteresis ^[6]	All inputs		0.2		V
V_{IK}	Input Clamp Diode Voltage	$V_{CC} = \text{Min.}$, $I_{IN} = -18\text{ mA}$		-0.7	-1.2	V
I_I	Input HIGH Current	$V_{CC} = \text{Max.}$, $V_{IN} = V_{CC}$			5	μA
I_{II}	Input HIGH Current	$V_{CC} = \text{Max.}$, $V_{IN} = 2.7\text{V}$			± 1	μA
I_{IL}	Input LOW Current	$V_{CC} = \text{Max.}$, $V_{IN} = 0.5\text{V}$			± 1	μA
I_{OZH}	Off State HIGH-Level Output Current	$V_{CC} = \text{Max.}$, $V_{OUT} = 2.7\text{V}$			10	μA
I_{OZL}	Off State LOW-Level Output Current	$V_{CC} = \text{Max.}$, $V_{OUT} = 0.5\text{V}$			-10	μA
I_{OS}	Output Short Circuit Current ^[7]	$V_{CC} = \text{Max.}$, $V_{OUT} = 0.0\text{V}$	-60	-120	-225	mA
I_{OFF}	Power-Off Disable	$V_{CC} = 0\text{V}$, $V_{OUT} = 4.5\text{V}$			± 1	μA

Notes:

1. H = HIGH Voltage Level
2. L = LOW Voltage Level
3. X = Don't Care
4. Z = High Impedance
5. Unless otherwise noted, these limits are over the operating free-air temperature range.
6. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.
7. T_A is the "instant on" case temperature.

5. Typical values are at $V_{CC} = 5.0\text{V}$, $T_A = +25^{\circ}\text{C}$ ambient.
6. This parameter is guaranteed but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parametric tests, I_{OS} tests should be performed last.